[NIST Docket Number: 07-011]

Title: Thermometer Based On Dielectric Electromagnetic Resonators.

Abstract: The invention provides a new and innovative sapphire whispering gallery thermometer (SWGT) that is very robust and resistant to mechanical shock. The intrinsic frequency temperature dependence of the synthetic sapphire permittivity, coupled with the ease of locating the resonant frequency of a high-Q resonator, allows for the use of a whispering gallery mode resonator as a thermometer rather than as a frequency source. The temporal stability of sapphire as the thermometry material provides excellent long-term thermometric reproducibility. Temperature sensitivity and stability of response, as exhibited by measurement uncertainty determination, of less than 10 mK have been demonstrated.

[NIST Docket Number: 07-012US]

Title: Length Separation of Carbon Nanotubes by Centrifugation in a Dense Liquid.

Abstract: The invention provides a method for separating carbon nanotubes by length. The processes involve forming highly dispersed systems of the nanotubes followed by creating an array of layers in a centrifugation vessel.

[NIST Docket Number: 07–013US]

Title: Microfluidic Passive Sorting and Storage of Liquid Plugs Using Capillary Force.

Abstract: A three-dimensional microfluidic device for passive sorting and storing of liquid plugs is provided with homogeneous surfaces from the exposure of a photopolymer through binary masking motifs, i.e., arrays of opaque pixels on a transparency mask. The device includes sub-millimeter three-dimensional relief microstructures to aid in the channeling of fluids. The microstructures have topographically modulated features smaller than 100 micrometers.

[NIST Docket Number: 07-014US]

Title: Fabrication Method of Topographically Modulated Microstructures Using Pattern Homogenization With UV Light.

Abstract: The invention consists of a photolithographic technique for the fabrication of microstructures with arbitrary topography, which utilizes UV light and a binary transparency mask designed to trigger a homogenization effect on a photopolymer.

Dated: September 4, 2008.

Richard F. Kayser,

Chief Scientist.

[FR Doc. E8–21155 Filed 9–10–08; 8:45 am]

BILLING CODE 3510-13-P

DEPARTMENT OF COMMERCE

National Institute of Standards and Technology

Manufacturing Extension Partnership Advisory Board

AGENCY: National Institute of Standards and Technology, Department of Commerce.

ACTION: Notice of public meeting.

SUMMARY: Pursuant to the Federal Advisory Committee Act, 5 U.S.C. app. 2, notice is hereby given that the Manufacturing Extension Partnership (MEP) Advisory Board, National Institute of Standards and Technology (NIST) will meet Wednesday, October 22, 2008, from 11 a.m. to 5 p.m. The MEP Advisory Board is composed of 10 members appointed by the Director of NIST who were selected for their expertise in the area of industrial extension and their work on behalf of smaller manufacturers. The Board was established to fill a need for outside input on MEP. MEP is a unique program consisting of centers across the United States and Puerto Rico, with partnerships at the state, federal, and local levels. The Board works closely with MEP to provide input and advice on MEP's programs, plans, and policies. For this meeting, discussions will focus on updates of MEP current key initiatives, MEP's next generation strategic plan and opportunities for MEP in emerging industries. The agenda may change to accommodate Board business.

DATES: The meeting will convene October 22, 2008 at 11 a.m. and will adjourn at 5 p.m. on October 22, 2008.

ADDRESSES: The meeting will be held at The Inn & Conference Center, University of Maryland University College, 3501 University Blvd E, Adelphi, Maryland 20783. Anyone wishing to attend this meeting should submit name, e-mail address and phone number to Susan Hayduk (susan.hayduk@nist.gov or 301–975–5615) no later than October 17, 2008.

FOR FURTHER INFORMATION CONTACT:

Karen Lellock, Manufacturing Extension Partnership, National Institute of Standards and Technology, Gaithersburg, Maryland 20899–4800, telephone number (301) 975–4269.

Dated: September 2, 2008.

James M. Turner,

 $Deputy\, Director.$

[FR Doc. E8–21148 Filed 9–10–08; 8:45 am]

BILLING CODE 3510-13-P

DEPARTMENT OF COMMERCE

National Institute of Standards and Technology

[Docket No: 080626784-81166-02]

Technology Innovation Program Extension of Due Date for Proposals

AGENCY: National Institute of Standards and Technology (NIST), United States Department of Commerce.

ACTION: Notice.

SUMMARY: Due to technical difficulties, NIST is extending the deadline for proposal submission for its Technology Innovation Program competition to 3 p.m. Eastern Time, Monday, September 15, 2008. NIST will accept only paper submissions during the extended time period.

DATES: Paper submissions must be received no later than 3 p.m. Eastern Time, Monday, September 15, 2008. Review, selection, and grant award processing is expected to be completed by early December 2008.

ADDRESSES: Paper submissions must be sent to the National Institute of Standards and Technology, 100 Bureau Drive, Stop 4701, Gaithersburg, MD 20899–4701.

FOR FURTHER INFORMATION CONTACT:

Barbara Lambis via e-mail at barbara.lambis@nist.gov or telephone (301) 975–4447.

SUPPLEMENTARY INFORMATION: On July 15, 2008, the National Institute of Standards and Technology's (NIST) Technology Innovation Program (TIP) announced that it was soliciting highrisk, high reward research and development proposals for financial assistance (73 FR 40507). The due date for submission of all proposals was 3 p.m. Eastern Time, Thursday, September 4, 2008. Due to technical difficulties some proposers were unable to submit their proposals electronically on Thursday, September 4, 2008. In order to provide all interested parties the opportunity to submit a proposal for TIP, NIST is extending the solicitation period until 3 p.m. Eastern Time, Monday, September 15, 2008. Electronic proposals received between 3 p.m. and 11:59 p.m. Eastern Time on Thursday, September 4, 2008 will be deemed timely and given full consideration. Paper proposals received between 3 p.m. Eastern Time on Thursday, September 4, 2008 and September 11, 2008 will be deemed timely and given full consideration. During the extended solicitation period, NIST will accept only paper submissions. Proposers who attempted to submit electronic